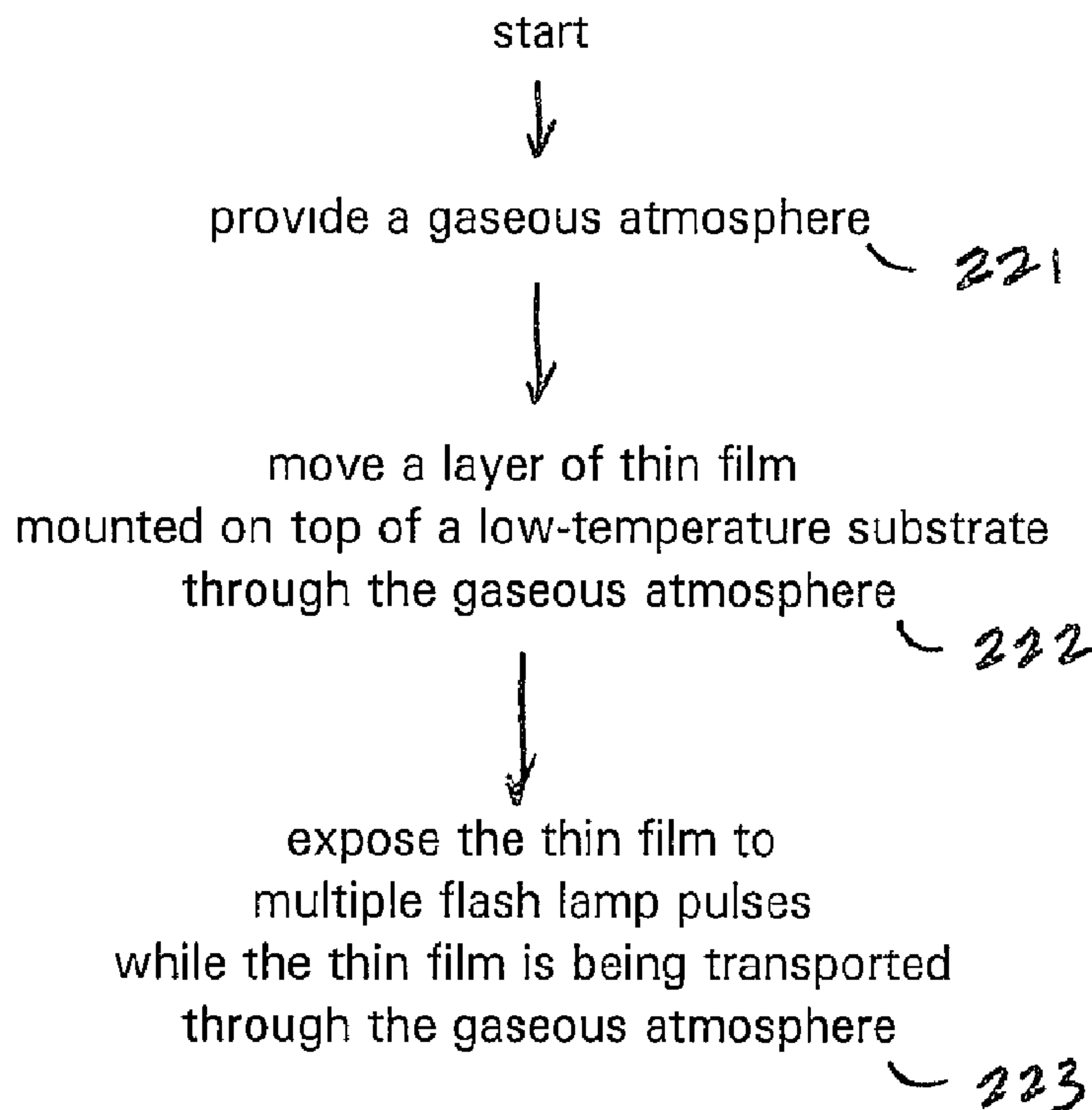




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TEMPERATURE A DE GRANDES VITESSES
 (54) Title: METHOD AND APPARATUS FOR REACTING THIN FILMS ON LOW-TEMPERATURE SUBSTRATES AT
HIGH SPEEDS



(57) **Abrégé/Abstract:**

A method for reacting thin films on a low-temperature substrate within a reactive atmosphere is disclosed. The thin film contains a reducible metal oxide, and the reactive atmosphere contains a reducing gas such as hydrogen or methane. The low temperature substrate can be polymer, plastic or paper. Multiple light pulses from a high intensity strobe system are used to reduce the metal oxide to metal and to sinter the metal if applicable.

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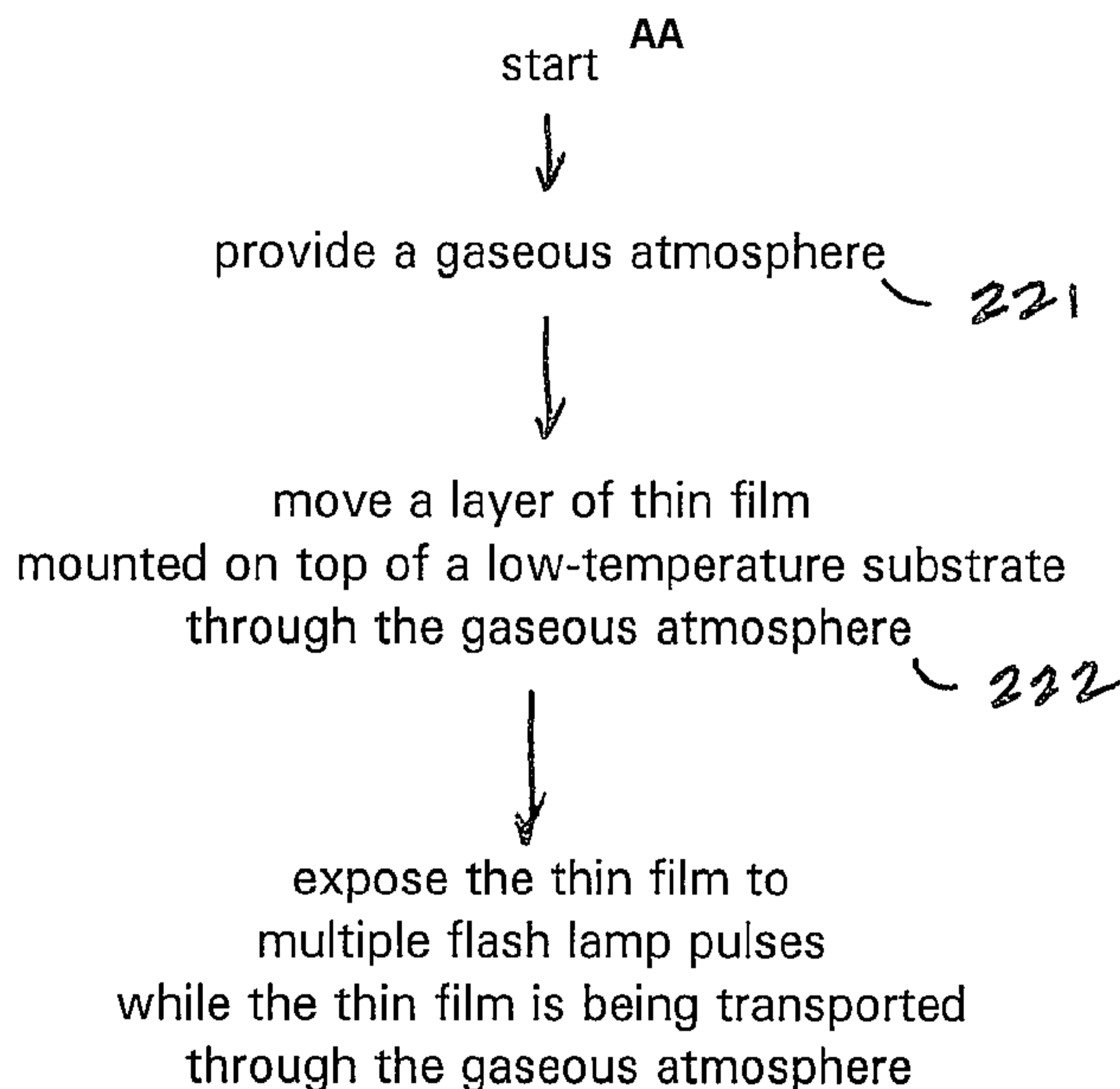
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(54) Title: METHOD AND APPARATUS FOR REACTING THIN FILMS ON LOW-TEMPERATURE SUBSTRATES AT HIGH SPEEDS



(57) Abstract: A method for reacting thin films on a low-temperature substrate within a reactive atmosphere is disclosed. The thin film contains a reducible metal oxide, and the reactive atmosphere contains a reducing gas such as hydrogen or methane. The low temperature substrate can be polymer, plastic or paper. Multiple light pulses from a high intensity strobe system are used to reduce the metal oxide to metal and to sinter the metal if applicable.

FIG. 2

1 **METHOD AND APPARATUS FOR REACTING THIN FILMS ON LOW-**
2 **TEMPERATURE SUBSTRATES AT HIGH SPEEDS**

3
4 **1. Technical Field**

5 The present invention relates to curing methods in general, and, in
6 particular, to a method and apparatus for reacting thin films on low-temperature substrates
7 at high speeds.

8 **2. Background**

9 One approach to making electrical conductors on circuits is to print metal-
10 containing ink onto a substrate, and to then heat the substrate for sintering the particles in
11 the metal-containing ink to form a conducting path. Generally, most metals suitable for
12 electrical conduction need to be heated to a very high temperature, which is often in the
13 range of a couple hundred degrees centigrade of their melting point. For example, silver is
14 a good metal for making conductive traces because it can be heated in air and that its
15 oxides, which are comparatively low in conductivity, decompose at relatively low
16 temperatures. In addition, the fact that silver being the most electrically conductive metal
17 often outweighs its high cost when comes to choosing a metal for making conductive
18 traces.

1 Another metal that is being constantly pursued in the manufacturing of
2 conductive traces is copper because of its low cost. Copper has about 90% of the
3 conductivity of silver but is usually 50 to 100 times cheaper than silver on a mass basis.
4 However, silver inks still dominate the printed electronics market because the additional
5 cost of making and processing the copper inks to avoid oxidation is generally higher than
6 the difference in cost of the bulk materials. Basically, when copper particles are heated in
7 air, they oxidize before they sinter, which results in a non-conductor.

8
9 Consequently, it would be desirable to provide an improved method for
10 making conductive traces using relatively low cost metals such as copper.

BRIEF DESCRIPTION OF THE DRAWINGS

1
2
3 The invention itself, as well as a preferred mode of use, further objects, and
4 advantages thereof, will best be understood by reference to the following detailed
5 description of an illustrative embodiment when read in conjunction with the accompanying
6 drawings, wherein:

7
8 Figure 1 is a diagram of a curing apparatus, in accordance with a preferred
9 embodiment of the present invention; and

10
11 Figure 2 is a high-level logic flow diagram of a method for reacting thin
12 films on a low-temperature substrate, in accordance with a preferred embodiment of the
13 present invention.

DETAILED DESCRIPTION OF A PREFERRED EMBODIMENT

1
2
3 It is well known that some metal oxides can be reduced by hydrogen or
4 hydrocarbons at an elevated temperature if they have a positive reduction potential.
5 Examples include oxides of copper, gold, platinum, and palladium. Copper can be made
6 by mixing copper oxide bearing ore with charcoal via a heating process. When oxidized
7 copper particles or even pure copper oxide is heated in a reducing atmosphere, the particles
8 can sinter to form a conductor.

9
10 When making thin film conductors by printing copper particles, a very
11 conductive trace can be formed if the particles are heated to their sintering temperature in
12 an inert or reducing atmosphere. Since the melting point of copper is nearly 1,085 °C, the
13 temperature required for sintering demands that only high-temperature substrates, such as
14 glass or ceramic, can be utilized. This relatively high temperature requirement on
15 substrates prevents the usage of inexpensive substrates such as paper or plastic.

16
17 Alternatively, if copper oxide is placed on a low-temperature substrate, the
18 copper oxide can be heated to near the substrate's decomposition temperature and the low-
19 temperature substrate can be placed in a reducing atmosphere. However, the low
20 temperature dramatically increases the amount of time needed to minutes or even hours
21 depending on the substrate thickness. Still, at these low temperatures, sintering is very
22 limited. The substrate temperature and gas atmosphere requirements can be overcome if
23 an intense, short pulse of light is utilized to cure the substrate. Unfortunately, these
24 approaches do nothing to address the residual oxide in the copper film. Reducible metal
25 oxide can be placed between two electrical contacts in a hydrogen atmosphere, and
26 electrical current can be repetitively pulsed through the oxide to heat the oxide and to
27 reduce the oxide. However, this technique requires electrical contacts and its throughput
28 is relatively limited. Thus, there is a need to reduce metal oxide on low-temperature
29 substrates with a high throughput.

30

1 For the present invention, curing is defined as thermal processing, which includes
2 reacting a thin film with a gaseous atmosphere. Thin film is defined as a coating less than
3 100 microns thick. A low-temperature substrate can be made of paper, plastic or polymer.
4 An electromagnetic emission may include electromagnetic radiation comprising gamma
5 rays, x-rays, ultraviolet, visible light, infrared, millimeter waves, microwaves, or
6 radiowaves. Electromagnetic emission sources include lasers, induction heaters, microwave
7 generators, flashlamps, light emitting diodes, etc.

8
9 Referring now to the drawings and in particular to Figure 1, there is depicted
10 a diagram of a curing apparatus, in accordance with a preferred embodiment of the present
11 invention. As shown, a curing apparatus 100 includes a conveyor belt system 110, a strobe
12 head 120, a relay rack 130 and a reel-to-reel feeding system 140. Curing apparatus 100
13 is capable of curing a thin film 102 mounted on a low-temperature substrate 103 situated
14 on a web being moved across a conveyor belt at a relative high speed. Conveyor belt
15 system 110 can operate at speeds from 0 to 1,000 ft/min, for example, to move substrate
16 103. Curing apparatus 100 can accommodate a web of any width in 6-inch increments.
17 Thin film 102 can be added on substrate 103 by one or combinations of existing
18 technologies such as screen printing, inkjet printing, gravure, laser printing, xerography, pad
19 printing, painting, dip-pen, syringe, airbrush, flexographic, chemical vapor deposition
20 (CVD), evaporation, sputtering, etc.

21
22 Strobe head 120, which is preferably water cooled, includes a high-intensity
23 pulsed xenon flash lamp 121 for curing thin film 102 located on substrate 103. Pulsed
24 xenon flash lamp 121 can provide pulses for different intensity, pulse length, and pulse
25 repetition frequency. For example, pulsed xenon flash lamp 121 can provide 10
26 microseconds to 50 milliseconds pulses with a 3" by 6" wide beam at a pulse repetition rate
27 of up to 1 kHz. The spectral content of the emissions from the pulsed xenon flash lamp
28 121 ranges from 200 nm to 2,500 nm. The spectrum can be adjusted by replacing the
29 quartz lamp with a cerium doped quartz lamp to remove most of the emission below 350
30 nm. The quartz lamp can also be replaced with a sapphire lamp to extend the emission

1 from approximately 140 nm to approximately 4,500 nm. Filters may also be added to
2 remove other portions of the spectrum. Flash lamp **121** can also be a water wall flash lamp
3 that is sometimes referred to a Directed Plasma Arc (DPA) lamp.
4

5 Relay rack **130** includes an adjustable power supply **131**, a conveyor control
6 module **132**, and a strobe control module **134**. Adjustable power supply **131** can produce
7 pulses with an energy of up to 4 kilojoules per pulse. Adjustable power supply **131** is
8 connected to pulsed xenon flash lamp **121**, and the intensity of the emission from pulsed
9 xenon flash lamp **121** can be varied by controlling the amount of current passing through
10 pulsed xenon flash lamp **121**.
11

12 Adjustable power supply **131** controls the emission intensity of pulsed xenon
13 flash lamp **121**. The power, pulse duration and pulse repetition frequency of the emission
14 from pulsed xenon flash lamp **121** are electronically adjusted and synchronized to the web
15 speed to allow optimum curing of thin film **102** without damaging substrate **103**, depending
16 on the optical, thermal and geometric properties of thin film **102** and substrate **103**.
17

18 During curing operation, substrate **103** as well as thin film **102** are being
19 moved onto conveyor belt system **110**. Conveyor belt system **110** moves thin film **102**
20 under strobe head **120** where thin film **102** is cured by rapid pulses from pulsed xenon flash
21 lamp **121**. The power, duration and repetition rate of the emissions from pulsed xenon
22 flash lamp **121** are controlled by strobe control module **134**, and the speed at which
23 substrate **103** is being moved past strobe head **120** is determined by conveyor control
24 module **132**.
25

26 A sensor **150**, which can be a mechanical, electrical, or optical sensor, is
27 utilized to sense the speed of conveyor belt system **110**. For example, the conveyor belt
28 speed of conveyor belt system **110** can be sensed by detecting a signal from a shaft encoder
29 connected to a wheel that made contact with the moving conveyor belt. In turn, the pulse

1 repetition rate can be synchronized with the conveyor belt speed of conveyor belt system
2 **110** accordingly. The synchronization of the strobe pulse rate f is given by:

$$3 \quad f = \frac{0.2 * S * O}{W}$$

4
5
6
7
8 *where* $f =$ strobe pulse rate [Hz]
9 $S =$ web speed [ft/min]
10 $O =$ overlap factor
11 $W =$ curing head width [in]

12
13 Overlap factor O is the average number of strobe pulses that are received by a substrate.
14 For example, with a web speed of 200 ft/min, and overlap factor of 5, and a curing head
15 width of 2.75 inches, the pulse rate of a strobe is 72.7 Hz.

16
17 An enclosure **160** surrounds substrate **103** and contains a reducing
18 atmosphere **161**. A transparent window **162** passes light from flash lamp **121**. When flash
19 lamp **121** is pulsed, film **102** is momentarily heated and chemically reacts with atmosphere
20 **161**. When a rapid pulse train is combined with moving substrate **103**, a uniform cure can
21 be attained over an arbitrarily large area as each section of thin film **102** is exposed to
22 multiple pulses, which approximates a continuous curing system such as an oven.

23
24 With reference now to Figure 2, there is depicted a high-level logic flow
25 diagram of a method for reacting thin films on a low-temperature substrate, in accordance
26 with a preferred embodiment of the present invention. Initially, a gaseous atmosphere
27 containing a reducing gas, such as reducing atmosphere **161** from Figure 1, is provided, as
28 shown in block **221**. Preferably, the gaseous atmosphere contains hydrogen or a
29 hydrocarbon such as methane, propane, etc.

1 Next, a layer of thin film located on top of a low-temperature substrate is
2 move through the gaseous atmosphere, as depicted in block **222**. The thin film preferably
3 contains a reducible metal oxide such as copper oxide (CuO), gold oxide (Ag₂O), platinum
4 oxide (PtO) and palladium oxide (PdO), etc. For reasons of economy, copper is desirable
5 as a conductor for printed electronics. A printed copper film often contains copper oxide,
6 which is a barrier to electronic conduction. The low-temperature substrate can be made of
7 polymer or paper.

8
9 Each segment (*i.e.*, the curing head width) of the layer of thin film is then
10 exposed to at least one pulse from a flash lamp, such as flash lamp **121** from Figure 1,
11 while the layer of thin film is being transported through the gaseous atmosphere, as shown
12 in block **223**, to allow the layer of thin film to be chemically reacted with the gaseous
13 atmosphere. Basically, the pulses from the strobe system reduce the thin film of metal
14 oxide, such as copper oxide, on the low-temperature substrate to form a conductive metal
15 film, such as copper film, in less than one second without damaging the low-temperature
16 substrate.

17
18 When reducing a metal oxide to a metal in a hydrogen environment, the
19 speed at which the reaction progresses is diffusion limited. The diffusion rate is related to
20 the temperature of the curing system. When an oven is utilized, the temperature is limited
21 by the decomposition temperature of the low-temperature substrate. The pulsed light heats
22 the metal oxide to a very high temperature without decomposing the low-temperature
23 substrate. This dramatically reduces the time to reduce the metal oxide.

24
25 As has been described, the present invention provides a method and
26 apparatus for reacting thin films on low-temperature substrates. One advantage of the
27 present invention is that a metal thin film can be obtained even when pure metal oxide is
28 initially deposited. One of the motivations to deposit metal oxide particles is that they are
29 more readily available than their metal counterparts, particularly when they are in a
30 nanoparticle form. It is particularly difficult to make very fine (tens of nm) metal particles

1 while maintaining their purity. The very fine metal particles are usually coated with either
2 an oxide and/or a capping group. In addition, metal oxide particles can be more easily
3 dispersed, and can be more easily printed on a variety of substrates.
4

5 Another advantage of the present invention is that it requires no registration.
6 If the thin film is a printed pattern, only that pattern is reacted while the unprinted portions
7 of the low-temperature substrate that generally are less absorptive of the light pulses are left
8 cool.
9

10 While the reduction of a metal oxide is shown to be in a reducing
11 atmosphere to form a metal film, other film/reactive gas combinations are also possible.
12 Other examples include:
13

- 14 (1) Reduction with H₂ (or creation of hydrides for H₂ storage materials).
15
- 16 (2) Oxidation with O₂ (for dielectrics).
17
- 18 (3) Carburization with carbonaceous gases for the formation of carbides. The
19 partial pressure of O₂ within the carbonaceous gas stream for the formation
20 of oxycarbides.
21
- 22 (4) Nitridation with ammonia or amines for the formation of nitrides. The
23 partial pressure of O₂ within the ammonia or amine gas stream for the
24 formation of oxynitrides.
25
- 26 (5) Formation of chalcogenides from various precursor gases. Chalcogenides
27 are sulfides (S²⁻), selenides (Se²⁻), and tellurides (Te²⁻). This covers a large
28 family of semiconductors (II - VI semiconductors), *e.g.*, ZnS, ZnSe, CdS,
29 CdSe, CdTe, etc.
30

1 (6) Formation of pnictides from various precursor gases. Pnictides are
2 phosphides (P^{3-}), arsenides (As^{3-}), and antimonides (Sb^{3-}). This also covers
3 the synthesis of a large family of semiconductors (III - V class
4 semiconductors), e.g., GaP, GaAs, InP, InAs, InSb, etc.

5 While the invention has been particularly shown and described with reference
6 to a preferred embodiment, it will be understood by those skilled in the art that various
7 changes in form and detail may be made therein without departing from the scope of the
8 invention.

CLAIMS

- 1
2
3
4 1. A curing apparatus comprising:
5 an enclosure configured to contain a hydrogen-bearing gas;
6 a strobe head having a flash lamp for providing a pulsed electromagnetic emission
7 to a layer of thin film mounted on a low-temperature substrate to allow said layer of thin
8 film to be chemically reacted with a gas within said enclosure; and
9 a conveyor system for moving said layer of thin film within said enclosure in
10 relation to said strobe head, wherein said conveyor system moves said low-temperature
11 substrate at a speed that is synchronized with said repetition rate of said pulsed
12 electromagnetic emission; and
13 a strobe control module for controlling power, duration, repetition rate and the
14 number of said pulse electromagnetic emission generated by said flash lamp.
15
16 2. The curing apparatus of Claim 1, wherein said low-temperature substrate is
17 made of paper.
18
19 3. The curing apparatus of Claim 1, wherein said gas contains hydrocarbon.
20
21 4. The curing apparatus of Claim 1, wherein said layer of thin film is a
22 metal compound containing a metal having a positive reduction potential.
23
24 5. The curing apparatus of Claim 1, wherein said layer of thin film is a metal
25 oxide.

1 6. The curing apparatus of Claim 1, wherein said synchronization is given by

2

$$f = \frac{0.2 \times S \times O}{W}$$

3

4 wherein f = strobe pulse rate,

5 S = web speed,

6 O = overlap factor indicating an average number of strobe
7 pulses received by said thin film, and

8 W = curing head width.

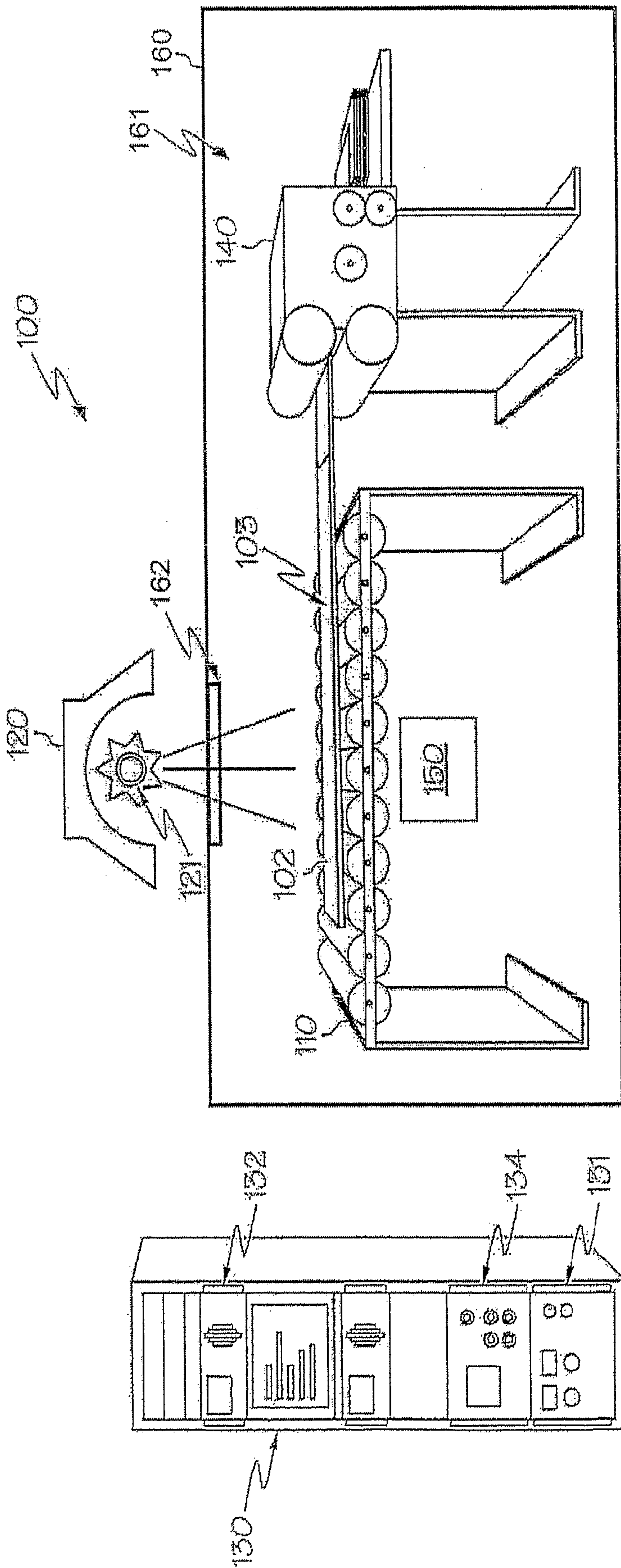


FIG. 1

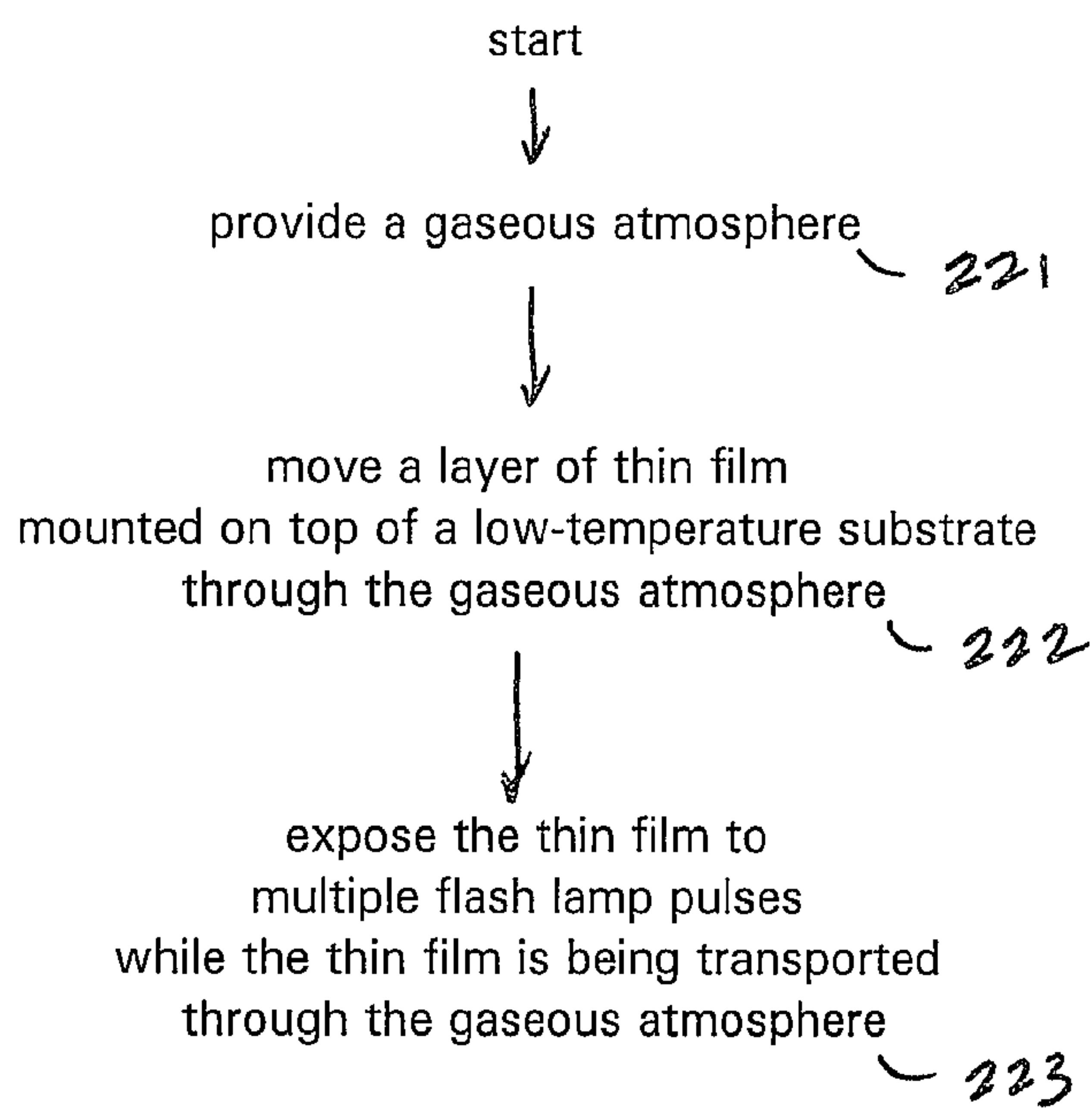


FIG. 2

start



provide a gaseous atmosphere

221



move a layer of thin film
mounted on top of a low-temperature substrate
through the gaseous atmosphere

222



expose the thin film to
multiple flash lamp pulses
while the thin film is being transported
through the gaseous atmosphere

223